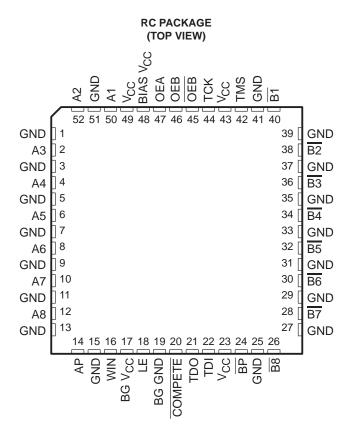
- Compatible With IEEE Std 1194.1-1991 (BTL)
- TTL A Port, Backplane Transceiver Logic (BTL) B Port
- Open-Collector B-Port Outputs Sink 100 mA
- BIAS V_{CC} Pin Minimizes Signal Distortion During Live Insertion or Withdrawal
- High-Impedance State During Power Up and Power Down
- B-Port Biasing Network Preconditions the Connector and PC Trace to the BTL High-Level Voltage
- TTL-Input Structures Incorporate Active Clamping Networks to Aid in Line Termination
- Packaged in Plastic Quad Flatpack



description

The SN74FB2032 device is a 9-bit transceiver designed to translate signals between TTL and backplane transceiver logic (BTL) environments and to perform bus arbitration. It is designed specifically to be compatible with IEEE Std 1194.1-1991.

The \overline{B} port operates at BTL-signal levels. The open-collector \overline{B} ports are specified to sink 100 mA and have minimum output edge rates of 2 ns. Two output enables (OEB and \overline{OEB}) are provided for the \overline{B} outputs. When OEB is low, \overline{OEB} is high, or V_{CC} is less than 2.1 V, the \overline{B} port is turned off.



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description (continued)

The A port operates at TTL-signal levels. The A outputs reflect the inverse of the data at the \overline{B} port when the A-port output enable, OEA, is high. When OEA is low or when V_{CC} is less than 2.1 V, the A outputs are in the high-impedance state.

The A-port data is latched when the latch enable (LE) is high. When LE is low, the latches are transparent.

The Futurebus protocol logic can be activated by taking $\overline{\text{COMPETE}}$ low. The module (device) then compares its A data (arbitration number) against the A data of another identical module also connected to the $\overline{\text{B}}$ arbitration bus, and sets WIN high if the A data is greater than the A data of the other module (i.e., has higher priority). A8 and $\overline{\text{B8}}$ are the most-significant bits, and A1 and $\overline{\text{B1}}$ are the least-significant bits. If OEB is high and $\overline{\text{OEB}}$ is low during this operation, and the A bus of the first module wins priority, the A bus asserts its arbitration number on the $\overline{\text{B}}$ -arbitration bus.

AP and \overline{BP} are the bus-parity bits. The winning module can assert \overline{BP} low if its parity bit (AP) is high.

In a typical operating sequence, a Futurebus arbitration controller latches its arbitration number into the A port and waits for the results of a competition. When the competition is complete, and if the controller's arbitration number did not win, the controller reads back the current value of the \overline{B} bus (by taking OEA high) and determines the winning arbitration number. This allows the module to change its arbitration number for the next competition cycle, if desired.

Pins are allocated for the four-wire IEEE Std 1149.1 (JTAG) test bus. TMS and TCK are not connected and TDI is shorted to TDO.

BIAS V_{CC} establishes a voltage between 1.62 V and 2.1 V on the BTL outputs when V_{CC} is not connected.

BG V_{CC} and BG GND are the supply inputs for the bias generator.

The SN74FB2032 is characterized for operation from 0°C to 70°C.



Function Tables

TRANSCEIVER

	INPUTS		FUNCTION			
OEA	OEB	OEB	FUNCTION			
L	Н	L	A data to B bus			
Н	L	Х	B data to A bus			
Н	Χ	Н				
Н	Н	L	\overline{A} data to B bus, \overline{B} data to A bus			
L	L	Χ	Isolation			
L	Χ	Н	isolation			

WIN

	INPUTS					
OEB	OEB OEB COMP		DATA A1, A2†	WIN		
Н	Н	Х	Х	L		
Н	L	Н	Х	L		
Н	L	L	A1 < A2	L		
Н	L	L	A2 ≤ A1	Н		

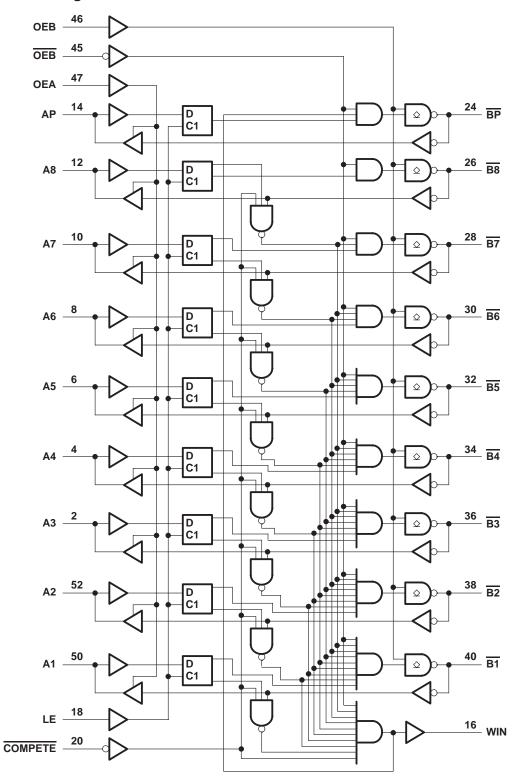
[†]A1 refers to the A data of Module 1 and A2 refers to the A data of Module 2. If LE = L, A = current A data. If LE = H, A = the value of A8–A1 prior to the most recent low-to-high transition of LE.

BP

	INP	INPUTS				
OEB	OEB	WIN	AP‡	BP		
L	Х	Χ	Х	Н		
Х	Н	Χ	X	Н		
Н	L	L	X	Н		
Н	L	Н	L	Н		
Н	L	Н	Н	L		

‡ If LE = L, AP = current AP data. If LE = H, AP = the level of AP prior to the most recent low-to-high transition of LE.

functional block diagram





absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC}	–0.5 V to 7 V
Input voltage range, V _I : Except BP, B port	–1.2 V to 7 V
BP, B port	–1.2 V to 3.5 V
Voltage range applied to any \overline{B} output in the disabled or power-off state, V_O	
Voltage range applied to any output in the high state, VO	
Input clamp current, I _{IK} : Except B port	–40 mA
B port	−18 mA
Current applied to any single output in the low state, IO: A port	48 mA
<u>B</u> port	200 mA
Package thermal impedance, θ _{JA} (see Note 1)	44°C/W
Storage temperature range, T _{stq}	–65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 2)

			MIN	NOM	MAX	UNIT
VCC, BIAS V _{CC} , BG V _{CC}	Supply voltage		4.5	5	5.5	V
V	High level input valtage	BP, B port	1.62		2.3	V
VIH	High-level input voltage	Except B port	2		V	
V	Low level input voltage	BP, B port	0.75 1.47		V	
V _{IL}	Low-level input voltage	Except B port			0.8	v
lıK	Input clamp current				-18	mA
loн	High-level output current	AP, WIN, A port			-3	mA
la.	Louis louis autout aureant	AP, WIN, A port			24	A
lOL	Low-level output current	BP, B port	100			mA
T _A	Operating free-air temperature	•	0		70	°C

NOTE 2: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST	CONDITIONS	MIN	TYP [†]	MAX	UNIT
Vina	BP, B port	V _{CC} = 4.5 V,	I _I = -18 mA			-1.2	V
VIK	Except BP, B port	V _{CC} = 4.5 V,	I _I = -40 mA			-0.5	V
Vall	AP, WIN, A port	V _{CC} = 4.5 V	I _{OH} = -1 mA				V
VOH	Ar, Will, A port	VCC = 4.5 V	$I_{OH} = -3 \text{ mA}$	2.5	3.3		V
	AP, WIN, A port	V _{CC} = 4.5 V	$I_{OL} = 20 \text{ mA}$				
V/01		VCC = 4.5 V	$I_{OL} = 24 \text{ mA}$		0.35	0.5	V
VOL		V _{CC} = 4.5 V	$I_{OL} = 80 \text{ mA}$	0.75		1.1	v
	BP, B port	VCC = 4.5 V	I _{OL} = 100 mA			1.15	
Ц	Except BP, B port	$V_{CC} = 5.5 V,$	V _I = 5.5 V			50	μΑ
I _{IH} ‡	Except BP, B port	$V_{CC} = 5.5 \text{ V},$	V _I = 2.7 V			50	μΑ
I _{IL} ‡	Except BP, B port	$V_{CC} = 5.5 \text{ V},$	V _I = 0.5 V			-50	μА
	BP, B port	V _{CC} = 5.5 V,	V _I = 0.75 V			-100	μΑ
lozh	AP, WIN, A port	$V_{CC} = 2.1 \text{ V to } 5.5 \text{ V},$	$V_0 = 2.7 \text{ V}$			50	mA
lozL	AP, WIN, A port	$V_{CC} = 2.1 \text{ V to } 5.5 \text{ V},$	V _O = 0.5 V			-50	mA
lozpu	AP, WIN, A port	$V_{CC} = 0 \text{ V to } 2.1 \text{ V},$	$V_0 = 0.5 \text{ V to } 2.7 \text{ V}$			50	mA
lozpd	AP, WIN, A port	$V_{CC} = 2.1 \text{ V to 0 V},$	$V_0 = 0.5 \text{ V to } 2.7 \text{ V}$			-50	mA
ІОН	BP, B port	$V_{CC} = 0 \text{ to } 5.5 \text{ V},$	V _O = 2.1 V			100	μΑ
los§	AP, WIN, A port	V _{CC} = 5.5 V,	VO = 0	-30		-150	mA
100	A port to B port	Vac 55V	la 0			55	mA
Icc	B port to A port	V _{CC} = 5.5 V,	IO = 0			65	IIIA
Ci	Control Inputs	V _I = 0.5 V or 2.5 V			4		pF
Co	WIN port	V _O = 0.5 V or 2.5 V			8		pF
	A port	V _O = 0.5 V to 2.5 V			7		
C _{io}	B port per IEEE Std 1194.1-1991	V _{CC} = 0 V to 5.5 V			·	5	pF

live-insertion specifications over recommended operating free-air temperature range

PAR	PARAMETER TEST CONDITIONS		MIN	MAX	UNIT		
Lice (BIAS Vec)		V _{CC} = 0 to 4.5 V	$V_B = 0 \text{ to } 2 \text{ V},$ $V_I \text{ (BIAS V}_{CC}) = 4.5 \text{ V to } 5.5 \text{ V}$			450	μA
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$				10	μΑ
VO	B port	$V_{CC} = 0$,	V_{I} (BIAS V_{CC}) = 5 V		1.62	2.1	V
		$V_{CC} = 0$,	$V_B = 1 V$,	V_I (BIAS V_{CC}) = 4.5 V to 5.5 V	-1		
IO \overline{B} port $\overline{V}_{CC} = 0$ to 5.5 V, $\overline{V}_{CC} = 0$ to 2.2 V,		$V_{CC} = 0 \text{ to } 5.5 \text{ V},$	OEB = 0 to 0.8 V			100	μΑ
		$V_{CC} = 0 \text{ to } 2.2 \text{ V},$	OEB = 0 to 5 V			100	



[†] All typical values are at V_{CC} = 5 V, T_A = 25°C. ‡ For I/O ports, the parameters I_{IH} and I_{IL} include the off-state output current. § Not more than one output should be shorted at a time, and the duration of the short circuit should not exceed one second.

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timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)

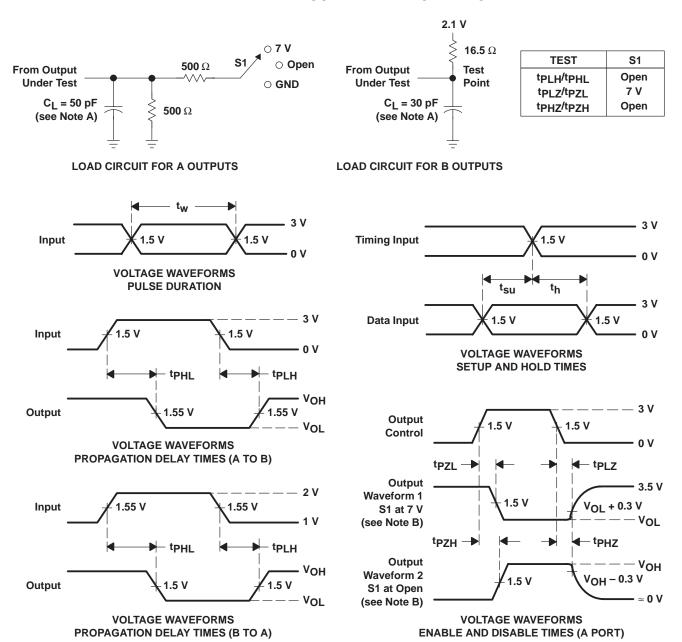
				V _{CC} = 5 V, T _A = 25°C		MAX	UNIT
			MIN	MAX			
t _W	Pulse duration	LE high or low	3.3		3.3		ns
		Data high before LE↑ (A to B)	1.5		1.5		
١.	Catus time	Data low before LE↑			1.4		
t _{su}	Setup time	Data high before LE↑ (A to WIN)		1.9		ns	
		Data low before LE↑	1.7		1.7		
		Data high before LE↑ (A to B)	1.7		1.7		
١.		Data low after LE↑	1.3		1.3		
t _h	Hold time	Data high before LE↑ (A to WIN)	1.6		1.6		ns
		Data low after LE↑	0.9		0.9		

switching characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)

F	PARAMETER	FROM (INPUT)	TO (OUTPUT)	V(V _{CC} = 5 V, T _A = 25°C		MIN	MAX	UNIT
		(1141 01)	(001101)	MIN	TYP	MAX			
	^t PLH	A or AP	B or BP	2.9	5.2	6.5	2.7	7	ns
	^t PHL	AUIAP	B or BP	3	4.9	6.3	2.8	6.6	115
	^t PLH	A	<u> </u>	3.1	5.6	7.4	2.5	8.4	ns
	^t PHL		<u>B</u> _{n − 1}	3.4	5.6	7.4	3.2	9	115
	^t PLH	A	BP	4.5	6.6	8.1	4	8.9	ns
	^t PHL		ВР	4.1	6.3	7.7	3.8	8.4	115
	^t PLH	B	<u> </u>	5.5	8.4	10.8	4.8	11.4	ns
	^t PHL	В	<u>B</u> n − 1	5.5	7.4	8.9	4.9	10	115
	^t PLH	LE	B or BP	3.7	5.6	6.8	3.4	7.3	no
	^t PHL		B OL Bb	3.5	5.1	6.1	3.1	6.8	ns
	^t PLH		4 45	3	5.3	7	2.9	7.2	
	^t PHL	B or BP	A or AP	2.8	4.6	5.9	2	6.1	ns
	^t PLH	_	14/15/	4	6	7.2	3.4	8.2	
	^t PHL	B	WIN	4.2	6.6	8.6	3.9	8.9	ns
	^t PLH	,	14/15/	1.9	4.1	5.4	1.7	5.9	
	^t PHL	- A	WIN	1.9	4	5.3	1.6	6	ns
	^t PLH			2.4	4.4	5.7	2.1	6.4	
	t _{PHL}	LE	WIN	1.9	3.5	4.5	1.6	4.9	ns
	tPLH	COMPETE		1.6	3.4	4.5	1.3	5	
	tPHL		WIN	1.7	3.4	4.4	1.5	4.9	ns
	tPLH			1.7	3.5	4.7	1.4	5.4	
	tPHL	OEB	WIN	2.2	3.8	4.7	2	5	ns
	tPLH		_	3.2	5.2	6.6	2.7	7.3	
	tPHL	COMPETE	B	3.8	5.6	6.7	3.5	7.3	ns
	t _{PLH}			3.9	6.2	7.6	3.8	7.8	
	tPHL	COMPETE	BP	3.9	5.7	7	3.4	7.8	ns
	tPLH			3.1	5.3	6.7	2.9	7.3	
	tPHL	OEB	B	3.4	5.4	6.7	3.2	7.2	ns
	tPLH			4.6	6.7	8.1	4.4	8.6	
	tPHL	OEB	B	3.7	5.9	8.1	3.4	8.9	ns
	t _{PZH}			2.5	4.3	6	2.2	6.3	
	t _{PZL}	OEA	A	2.2	3.9	5.3	2.2	5.8	ns
	t _{PHZ}	1		1.7	3.4	4.9	1.3	5.5	
	tPLZ	OEA	A	1.9	3.7	5.4	1.7	5.7	ns
		A		1	0.8	J		J	
tsk(p)	Pulse skew	$\frac{1}{\overline{B}}$	A	+	0.5				ns
	 	A	B	+	0.8				
tsk(o)	Pulse skew	B	A	+	0.6				ns
t _r	Rise time, 1.3 V to		<u> </u>	1	2.2	3.2	1	3.2	ns
tf	Fall time, 1.3 V to	•		1	1.3	2.3	1	2.5	ns
	input pulse rejection	·		1		0	1		ns



PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: TTL inputs: PRR \leq 10 MHz, Z_O = 50 Ω , $t_f \leq$ 2.5 ns, $t_f \leq$ 2.5 ns; BTL inputs: PRR \leq 10 MHz, Z_O = 50 Ω , $t_f \leq$ 2.5 ns.
- D. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuits and Voltage Waveforms



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